

Please delete the title and replace the title of the invention with the following:

--Method and Apparatus for Inspecting an Integrated Circuit by Measuring Voltage on a Signal Line--.

REMARKS

Claims 8 and 13 are pending in the application.

The Office action requires a new title more clearly indicative of the invention. The old title is deleted and a new title is provided as required.

The Office action rejects to claim 13 under 35 U.S.C. § 112, second paragraph. The Office action indicates that this rejection relates to an uncertainty as to whether the recited "current measuring device" and "voltage measuring device" are shown in the drawings. Applicants respectfully traverse this rejection. The recited voltage-measuring device 724 is shown in an example embodiment in FIG. 7. The recited current-measuring device that ~~comprises the voltage-measuring device 724 for that embodiment is~~ also shown in FIG. 7, and is identified therein according to the description beginning on page 11, line 25 of the specification, comprising items 208, 210, 718, 720, 722, 724 in that illustrated example. Accordingly, withdrawal of the rejection under 35 U.S.C. § 112, second paragraph is respectfully requested.

The Office action rejects claims 8 and 13 under 35 U.S.C. § 102(b) over U.S. Patent No. 5,162,742 to Atkins et al.

Applicants respectfully traverse this rejection. As explained below, claims 8 and 13 are patentable over the cited reference.

Atkins et al. teach a method for locating electrical shorts in multi-layered ceramic electrode substrates. Current flowing in a short-circuit 22 is measured by connecting two current source lines (electrical probes 32 and 34) from the same current source 30 to respective sides of the short-circuit 22. An ammeter 38 measures current passing through one of the current source lines 32. A voltmeter 38 is connected between the two current source lines 32 and 34.

Multiple elements of claims 18 and 13 are not found in the apparatus and method of Atkins et al. For example, claims 8 and 13 recite that voltage is measured over a segment of a signal line. Conversely, Atkins et al. measure voltage between two current source lines.

Additionally, claims 8 and 13 recite that current in a signal line of an integrated circuit is measured. Conversely, Atkins et al. measure only current passing through a current source line of a testing device.

Moreover, claims 8 and 13 recite that current in a signal line of an integrated circuit is measured based on measuring voltage over a segment of the signal line (i.e., the measured voltage is used in determining the current). Conversely, Atkins et

al. measure current and voltage separately and use them to calculate resistance.

Finally, claims 8 and 13 recite determining current in a signal line on the basis of voltage measured over a segment of a signal line. Conversely, Atkins et al. directly measure current over a segment of one current source line, while measuring voltage between two current source lines.

Because not all (indeed, practically none) of the elements recited in claims 8 and 13 are taught or suggested in the cited reference, withdrawal of the 35 U.S.C. § 102(b) rejection of claims 8 and 13 is respectfully requested.

In view of the foregoing, applicant(s) respectfully request(s) that the Examiner withdraw the rejections of record, allow all the pending claims, and find the present application to be in condition for allowance. If any points remain in issue that may best be resolved through a personal or telephonic interview, the Examiner is respectfully requested to contact the undersigned at the telephone number listed below.

Respectfully submitted,



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